


<b>Search Notes</b>  	<b>Application/Control No.</b>  10669443	<b>Applicant(s)/Patent Under Reexamination</b>  LEE, JEONG SIK
	<b>Examiner</b>  Haney, Richale L	<b>Art Unit</b>  3765

SEARCHED			
Class	Subclass	Date	Examiner
2	181, 195.1, 195.2, 195.3, 175.1, 184	7/20/2005	PN
above	updated	9/20/2005	RLH
2	181, 195.1, 195.2, 195.3, 175.1, 184	1/3/2007	RLH

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST printout	1/3/2007	RLH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
EAST	interference clm. search	1/3/2007	RLH